

COPY

U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)				Docket No. SEA/3369		Serial No.		
LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT (Use several sheets if necessary)				Applicant Shih-Fu Lee		Confirmation No.:		
Examiner JUN 06 2005				Filing Date		Group		
U.S. Patent Documents								
*Examiner Initial		Document Number	Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate	
✓	LDW	A1	6,618,215 B2	09-09-2003	Fung, et al.	360	31	03-06-2002
✓		A2	6,615,387 B1	09-02-2003	Williamson, et al.	714	785	09-02-2003
✓		A3	6,611,397 B1	08-26-2003	Nguyen, H.V.	360	77.08	06-04-1999
✓		A4	6,606,211 B1	08-12-2003	Lim, et al.	360	53	04-19-2000
✓		A5	6,603,636 B2	08-05-2003	Schwandt, et al.	360	99.12	06-29-2001
✓		A6	6,590,388 B2	07-08-2003	Arnaout, et al.	324	210	06-26-2001
✓		A7	6,587,293 B1	07-01-2003	Ding, et al.	360	51	02-29-2000
✓		A8	6,574,068 B1	06-03-2003	Hampshire, et al.	360	77.08	04-18-2000
✓		A9	6,483,299 B1	11-19-2002	Pressesky, et al.	324	212	11-09-2000
✓		A10	6,476,995 B1	11-05-2002	Liu, et al.	360	75	01-14-2000
✓		A11	6,405,449 B1	06-18-2002	Sundaram, et al.	33	645	02-07-2001
✓		A12	6,404,590 B1	06-11-2002	Kuo, et al.	360	135	03-18-1998
✓		A13	6,396,773 B1	05-28-2002	Kuo, D.S.	369	13.02	12-11-1998
✓		A14	6,387,530 B1	05-14-2002	Liu, et al.	428	559	06-14-2000
✓		A15	6,373,243 B1	04-16-2002	Takano, et al.	324	212	10-12-2000
Foreign Patent Documents								
*Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation	
							YES	NO
	B1						<input type="checkbox"/>	<input type="checkbox"/>
	B2						<input type="checkbox"/>	<input type="checkbox"/>
OTHER ART								
*Examiner Initial		Including Author, Title, Date, Pertinent Pages, Etc.						
LDW	C1	ECE Signals and Systems Fall, 2002, UMD, "Experiment 2: The Controls in the Spectrum Analyzer," 8 pages						
LDW	C2	"Spectrum Analyzer Updates," June 10, 2000, 15 pages						
LDW	C3	J. Mulder, "An RMS-DC Converter Based on the Dynamic Translinear Principle," IEEE Journal of Solid-State Circuits, Vol. 32, No. 7, July 1997, Pages 1146-1150						
Examiner 7/13/05				Date Considered 7/13/05				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.								

U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)		Docket No. SEA/3369	Serial No.
LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT (Use several sheets if necessary)		Applicant Shih-Fu Lee	Confirmation No.:
Examiner		Filing Date	Group

U.S. Patent Documents

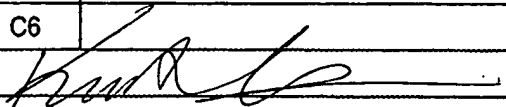
*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate	
✓	LSW	A16	6,359,747 B1	03-19-2002	Kuo, D.S.	360	75	08-07-1998
		A17	6,587,293 B1	07-01-2003	Ding, et al.	360	51	02-29-2000
✓		A18	6,580,572 B1	06-17-2003	Yao, et al.	360	25	12-14-2000
		A19	6,574,068 B1	06-03-2003	Hampshire, et al.	360	77.08	04-18-2000
✓		A20	6,304,407 B1	10-16-2001	Baker, et al.	360	75	10-27-1998
✓		A21	6,181,492 B1	01-30-2001	Bonyhard, P.I.	360	17	03-09-1998
✓		A22	6,142,006	11-07-2000	Marchon, et al.	73	1.81	07-24-1998
✓		A23	6,097,561	08-01-2000	Wakefield, et al.	360	51	03-09-1998
✓		A24	5,996,045	11-30-1999	Lee, et al.	711	112	07-08-1997
✓		A25	5,963,029	10-05-1999	Pressesky, J.L.	324	212	01-30-1997
✓		A26	5,991,104	11-23-1999	Bonyhard, P.I.	360	15	11-27-1996
		A27	5,898,499	04-27-1999	Pressesky, J.L.	356	357	01-30-1997
✓	✓	A28	2003/0035235 A1		Ikeda, et al.	360	59	08-07-2002

Foreign Patent Documents

*Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation	
							YES	NO
		B3					<input type="checkbox"/>	<input type="checkbox"/>
		B4					<input type="checkbox"/>	<input type="checkbox"/>
		B5					<input type="checkbox"/>	<input type="checkbox"/>
		B6					<input type="checkbox"/>	<input type="checkbox"/>

OTHER ART

*Examiner Initial		Including Author, Title, Date, Pertinent Pages, Etc.
LSW	C4	"RF Up/Down Conversion Is Simplified By Linear Arrays", Intersil™, Application Note 9744, July 1997, 4 pages
LSW	C5	http://whatis.techtarget.com/definition , 2 pages
	C6	

Examiner  Date Considered 7/13/05

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.